



TestForum 2008

Nordic Hotel Forum, Tallinn, Estonia
November 25th & 26th, 2008

Call for Papers / Presentations

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Sponsors of Nordic Test Forum



The 2 day TestForum 2008, the 9th event in the series, is a major event for Test professionals in the Nordic area and Baltic states. Every year the TestForum is attended by the industry's key persons as well as by international vendors of test and measurement equipment and solutions.

The event will take place at Nordic Hotel Forum (<http://www.nordichotels.eu>), which is located in the downtown of Tallinn nearby its medieval historic center.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2008, which includes (but is not limited to) the following topics:

- *Embedded Test*
- *Functional test*
- *AOI / AXI*
- *Test economics*
- *ICT / Flying Probe*
- *Boundary scan test*
- *Preventive test / Prognostics*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Testing Lead Free Electronics*
- *Design to Test transfer / Design for Testing*
- *Data acquisition / collection / analysis*
- *Quality methods and tools*
- *ESD*
- *Test efficiency and optimization*
- *Future technology trends and test challenges*
- *Data acquisition / collection / analysis*

Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are free to submit contributions outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities and techniques rather than on particular products.

Proceedings

At the event, Nordic Test Forum will deliver a CD-ROM of the accepted contributions of authors that wish to provide the corresponding materials.

The Format of the Event

- The event duration will be a two-day workshop and a small exhibition attached to it.
- November 24th on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- During the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Presentation slides:

September 16th, 2008

October 6^h, 2008

October 31th, 2008

Further Information and Submissions

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Visit the NTF web pages at:

<http://www.nordicestforum.org>

